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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	4548
Number of Logic Elements/Cells	90960
Total RAM Bits	4520448
Number of I/O	558
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1152-BBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2sgx90ef1152c4n

capable of built-in self test (BIST) generation and verification. The ALT2GXB megafunction in the Quartus II software provides a step-by-step menu selection to configure the transceiver.

Figure 2–1 shows the block diagram for the Stratix II GX transceiver channel. Stratix II GX transceivers provide PCS and PMA implementations for all supported protocols. The PCS portion of the transceiver consists of the word aligner, lane deskew FIFO buffer, rate matcher FIFO buffer, 8B/10B encoder and decoder, byte serializer and deserializer, byte ordering, and phase compensation FIFO buffers.

Each Stratix II GX transceiver channel is also capable of BIST generation and verification in addition to various loopback modes. The PMA portion of the transceiver consists of the serializer and deserializer, the CRU, and the high-speed differential transceiver buffers that contain pre-emphasis, programmable on-chip termination (OCT), programmable voltage output differential (V_{OD}), and equalization.

Transmitter Path

This section describes the data path through the Stratix II GX transmitter. The Stratix II GX transmitter contains the following modules:

- Transmitter PLLs
- Access to one of two PLLs
- Transmitter logic array interface
- Transmitter phase compensation FIFO buffer
- Byte serializer
- 8B/10B encoder
- Serializer (parallel-to-serial converter)
- Transmitter differential output buffer

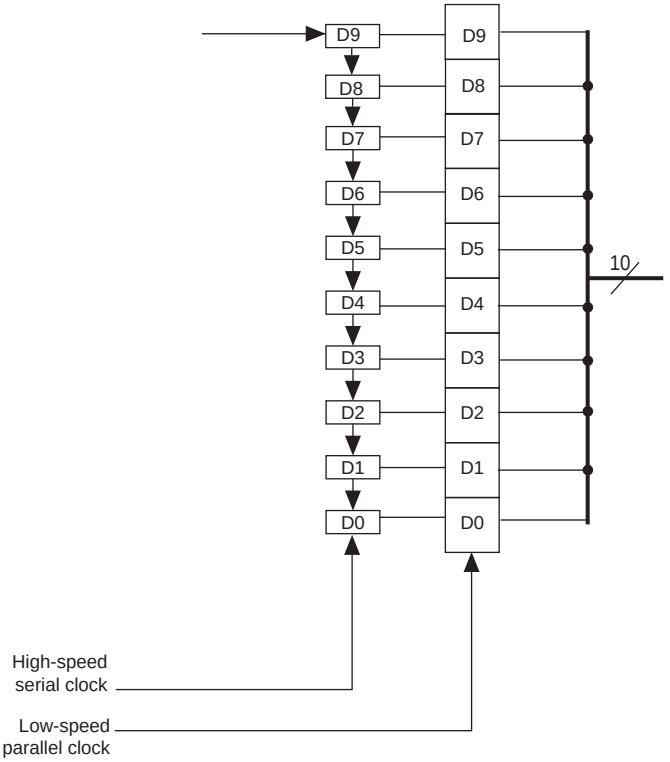
Transmitter PLLs

Each transceiver block has two transmitter PLLs which receive two reference clocks to generate timing and the following clocks:

- High-speed clock used by the serializer to transmit the high-speed differential transmitter data
- Low-speed clock to load the parallel transmitter data of the serializer

The serializer uses high-speed clocks to transmit data. The serializer is also referred to as parallel in serial out (PISO). The high-speed clock is fed to the local clock generation buffer. The local clock generation buffers divide the high-speed clock on the transmitter to a desired frequency on a per-channel basis. Figure 2–3 is a block diagram of the transmitter clocks.

Figure 2–17. Deserializer Note (1)



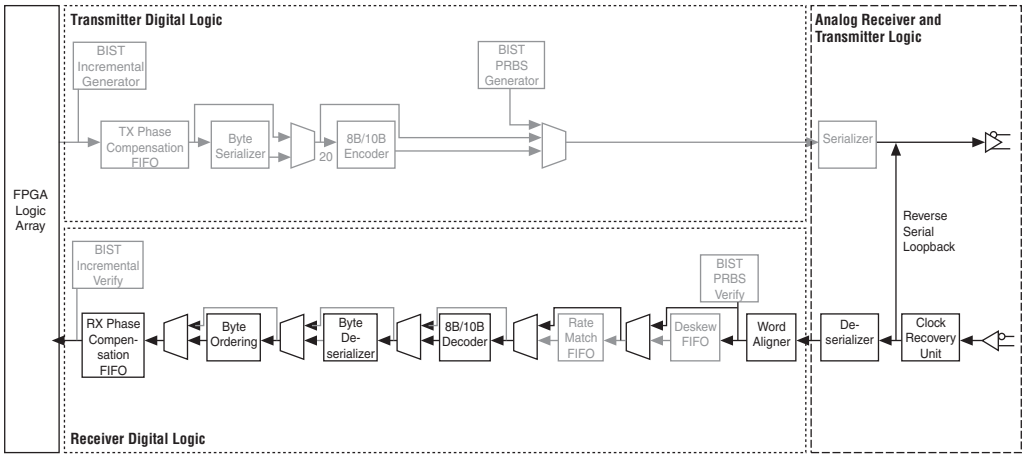
Note to Figure 2–17:
(1) This is a 10-bit deserializer. The deserializer can also convert 8, 16, or 20 bits of data.

Word Aligner

The deserializer block creates 8-, 10-, 16-, or 20-bit parallel data. The deserializer ignores protocol symbol boundaries when converting this data. Therefore, the boundaries of the transferred words are arbitrary. The word aligner aligns the incoming data based on specific byte or word boundaries. The word alignment module is clocked by the local receiver recovered clock during normal operation. All the data and programmed patterns are defined as big-endian (most significant word followed by least significant word). Most-significant-bit-first protocols such as SONET/SDH should reverse the bit order of word align patterns programmed.

Figure 2–26 shows the data path in reverse serial loopback mode.

Figure 2–26. Stratix II GX Block in Reverse Serial Loopback Mode

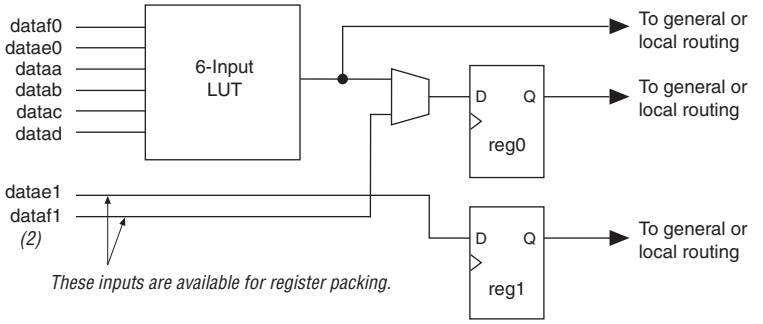


Reverse Serial Pre-CDR Loopback

The reverse serial pre-CDR loopback mode uses the analog portion of the transceiver. An external source (pattern generator or transceiver) generates the source data. The high-speed serial source data arrives at the high-speed differential receiver input buffer, loops back before the CRU unit, and is transmitted though the high-speed differential transmitter output buffer. It is for test or verification use only to verify the signal being received after the gain and equalization improvements of the input buffer. The signal at the output is not exactly what is received since the signal goes through the output buffer and the VOD is changed to the VOD setting level. The pre-emphasis settings have no effect.

using the bottom set of output drivers. The Quartus II Compiler automatically selects the inputs to the LUT. Asynchronous load data for the register comes from the `datae` or `dataf` input of the ALM. ALMs in normal mode support register packing.

Figure 2–39. 6-Input Function in Normal Mode *Notes (1), (2)*



Notes to Figure 2–39:

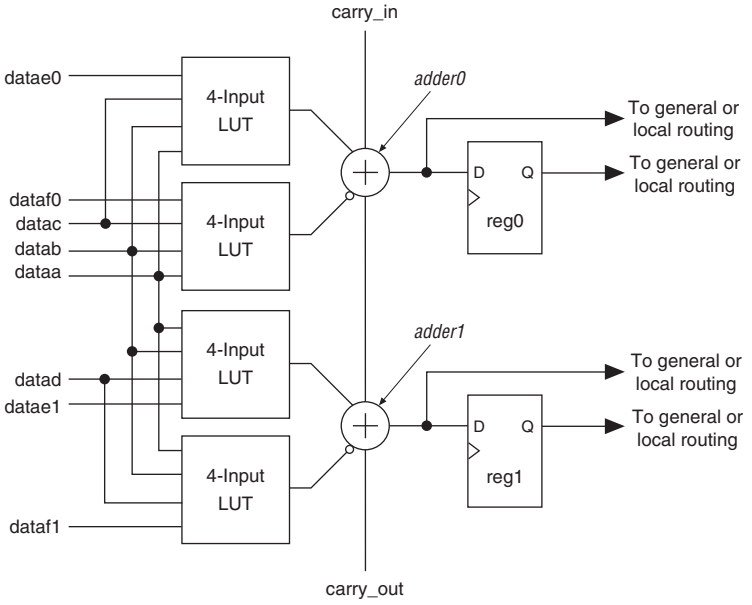
(1) If `datae1` and `dataf1` are used as inputs to the six-input function, `datae0` and `dataf0` are available for register packing.

(2) The `dataf1` input is available for register packing only if the six-input function is un-registered.

Extended LUT Mode

The extended LUT mode is used to implement a specific set of seven-input functions. The set must be a 2-to-1 multiplexer fed by two arbitrary five-input functions sharing four inputs. Figure 2–40 shows the template of supported seven-input functions utilizing extended LUT mode. In this mode, if the seven-input function is unregistered, the unused eighth input is available for register packing. Functions that fit into the template shown in Figure 2–40 occur naturally in designs. These functions often appear in designs as "if-else" statements in Verilog HDL or VHDL code.

Figure 2–41. ALM in Arithmetic Mode



While operating in arithmetic mode, the ALM can support simultaneous use of the adder's carry output along with combinational logic outputs. In this operation, the adder output is ignored. This usage of the adder with the combinational logic output provides resource savings of up to 50% for functions that can use this ability. An example of such functionality is a conditional operation, such as the one shown in Figure 2–42. The equation for this example is:

R = (X < Y) ? Y : X

To implement this function, the adder is used to subtract 'Y' from 'X'. If 'X' is less than 'Y', the `carry_out` signal will be '1'. The `carry_out` signal is fed to an adder where it drives out to the LAB local interconnect. It then feeds to the LAB-wide `syncload` signal. When asserted, `syncload` selects the `syncdata` input. In this case, the data 'Y' drives the `syncdata` inputs to the registers. If 'X' is greater than or equal to 'Y', the `syncload` signal is de-asserted and 'X' drives the data port of the registers.

Table 2–21 shows the number of DSP blocks in each Stratix II GX device. DSP block multipliers can optionally feed an adder/subtractor or accumulator in the block, depending on the configuration, which makes routing to ALMs easier, saves ALM routing resources, and increases performance because all connections and blocks are in the DSP block.

Table 2–21. DSP Blocks in Stratix II GX Devices *Note (1)*

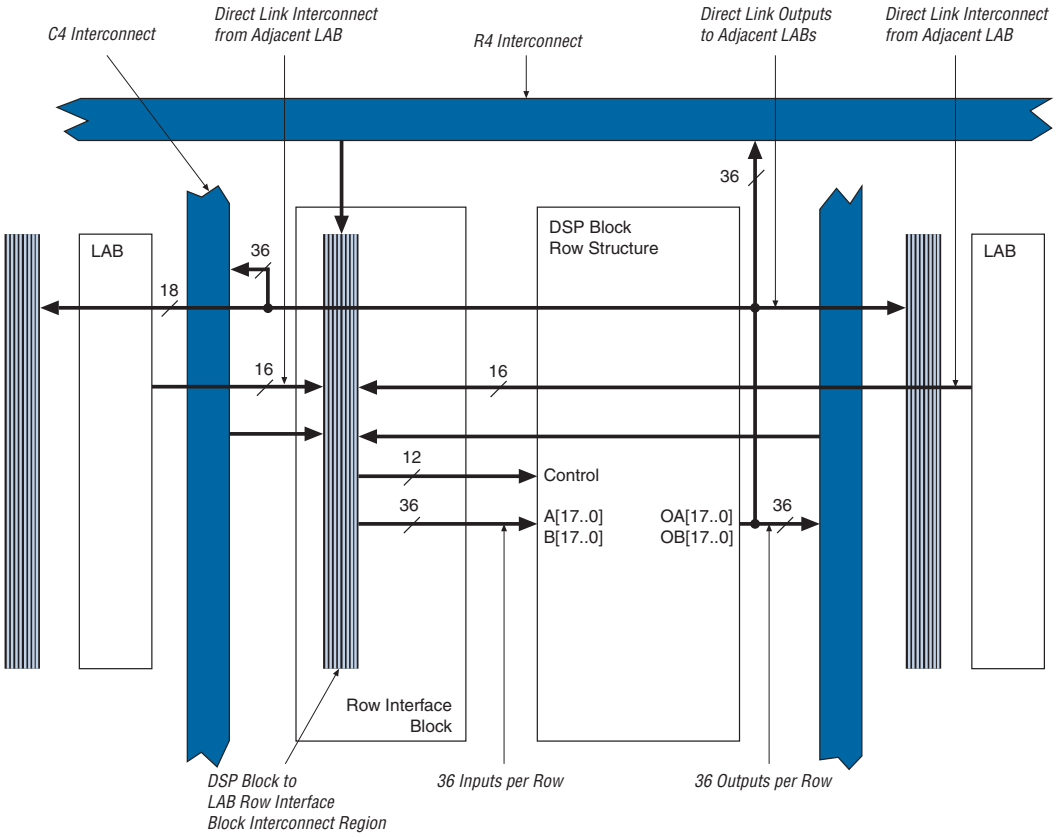
Device	DSP Blocks	Total 9 × 9 Multipliers	Total 18 × 18 Multipliers	Total 36 × 36 Multipliers
EP2SGX30	16	128	64	16
EP2SGX60	36	288	144	36
EP2SGX90	48	384	192	48
EP2SGX130	63	504	252	63

Note to Table 2–21:

(1) This list only shows functions that can fit into a single DSP block. Multiple DSP blocks can support larger multiplication functions.

Additionally, the DSP block input registers can efficiently implement shift registers for FIR filter applications, and DSP blocks support Q1.15 format rounding and saturation. Figure 2–58 shows the top-level diagram of the DSP block configured for 18 × 18-bit multiplier mode.

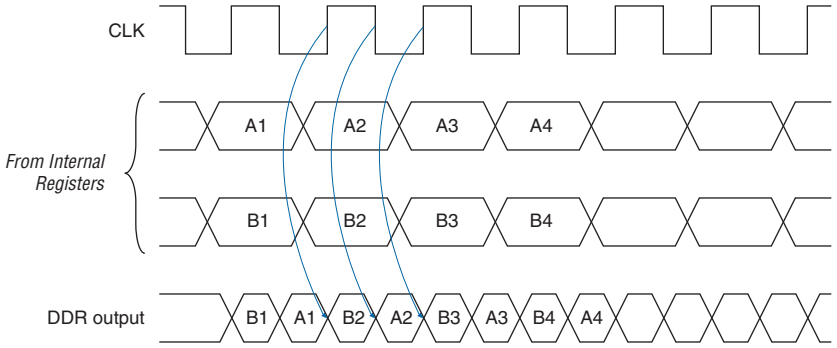
Figure 2–60. DSP Block Interface to Interconnect



A bus of 44 control signals feeds the entire DSP block. These signals include clocks, asynchronous clears, clock enables, signed and unsigned control signals, addition and subtraction control signals, rounding and saturation control signals, and accumulator synchronous loads. The clock signals are routed from LAB row clocks and are generated from specific LAB rows at the DSP block interface. The LAB row source for control signals, data inputs, and outputs is shown in Table 2–23.

Refer to the *DSP Blocks in Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook* for more information on DSP blocks.

Figure 2–85. Output Timing Diagram in DDR Mode



The Stratix II GX IOE operates in bidirectional DDR mode by combining the DDR input and DDR output configurations. The negative-edge-clocked OE register holds the OE signal inactive until the falling edge of the clock to meet DDR SDRAM timing requirements.

External RAM Interfacing

In addition to the six I/O registers in each IOE, Stratix II GX devices also have dedicated phase-shift circuitry for interfacing with external memory interfaces, including DDR and DDR2 SDRAM, QDR II SRAM, RLDRAM II, and SDR SDRAM. In every Stratix II GX device, the I/O banks at the top (banks 3 and 4) and bottom (banks 7 and 8) of the device support DQ and DQS signals with DQ bus modes of ×4, ×8/×9, ×16/×18, or ×32/×36. Table 2–31 shows the number of DQ and DQS buses that are supported per device.

Table 2–31. DQS and DQ Bus Mode Support

Device	Package	Number of ×4 Groups	Number of ×8/×9 Groups	Number of ×16/×18 Groups	Number of ×32/×36 Groups
EP2SGX30	780-pin FineLine BGA	18	8	4	0
EP2SGX60	780-pin FineLine BGA	18	8	4	0
	1,152-pin FineLine BGA	36	18	8	4
EP2SGX90	1,152-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4
EP2SGX130	1,508-pin FineLine BGA	36	18	8	4

On-Chip Termination

Stratix II GX devices provide differential (for the LVDS technology I/O standard) and series on-chip termination to reduce reflections and maintain signal integrity. On-chip termination simplifies board design by minimizing the number of external termination resistors required. Termination can be placed inside the package, eliminating small stubs that can still lead to reflections.

Stratix II GX devices provide four types of termination:

- Differential termination (R_D)
- Series termination (R_S) without calibration
- Series termination (R_S) with calibration
- Parallel termination (R_T) with calibration

Table 2–34 shows the Stratix II GX on-chip termination support per I/O bank.

Table 2–34. On-Chip Termination Support by I/O Banks (Part 1 of 2)

On-Chip Termination Support	I/O Standard Support	Top and Bottom Banks (3, 4, 7, 8)	Left Bank (1, 2)
Series termination without calibration	3.3-V LVTTL	✓	✓
	3.3-V LVCMOS	✓	✓
	2.5-V LVTTL	✓	✓
	2.5-V LVCMOS	✓	✓
	1.8-V LVTTL	✓	✓
	1.8-V LVCMOS	✓	✓
	1.5-V LVTTL	✓	✓
	1.5-V LVCMOS	✓	✓
	SSTL-2 class I and II	✓	✓
	SSTL-18 class I	✓	✓
	SSTL-18 class II	✓	—
	1.8-V HSTL class I	✓	✓
	1.8-V HSTL class II	✓	—
	1.5-V HSTL class I	✓	✓
	1.2-V HSTL	✓	—

On-Chip Parallel Termination with Calibration

Stratix II GX devices support on-chip parallel termination with calibration for column I/O pins only. There is one calibration circuit for the top I/O banks and one circuit for the bottom I/O banks. Each on-chip parallel termination calibration circuit compares the total impedance of each I/O buffer to the external 50-Ω resistors connected to the RUP and RDN pins and dynamically enables or disables the transistors until they match. Calibration occurs at the end of device configuration. Once the calibration circuit finds the correct impedance, it powers down and stops changing the characteristics of the drivers.

On-chip parallel termination with calibration is only supported for input pins.

For more information about on-chip termination supported by Stratix II devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

For more information about tolerance specifications for on-chip termination with calibration, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook.*

MultiVolt I/O Interface

The Stratix II GX architecture supports the MultiVolt I/O interface feature that allows Stratix II GX devices in all packages to interface with systems of different supply voltages. The Stratix II GX VCCINT pins must always be connected to a 1.2-V power supply. With a 1.2-V V_{CCINT} level, input pins are 1.2-, 1.5-, 1.8-, 2.5-, and 3.3-V tolerant. The VCCIO pins can be connected to either a 1.2-, 1.5-, 1.8-, 2.5-, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (for example, when VCCIO pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). The Stratix II GX VCCPD power pins must be connected to a 3.3-V power supply. These power pins are used to supply the pre-driver power to the output buffers, which increases the performance of the output pins. The VCCPD pins also power configuration input pins and JTAG input pins.

3. Configuration & Testing

SIIGX51005-1.4

IEEE Std. 1149.1 JTAG Boundary-Scan Support

All Stratix® II GX devices provide Joint Test Action Group (JTAG) boundary-scan test (BST) circuitry that complies with the IEEE Std. 1149.1. You can perform JTAG boundary-scan testing either before or after, but not during configuration. Stratix II GX devices can also use the JTAG port for configuration with the Quartus® II software or hardware using either Jam Files (**.jam**) or Jam Byte-Code Files (**.jbc**).

Stratix II GX devices support IOE I/O standard setting reconfiguration through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode through the `CONFIG_IO` instruction. You can use this capability for JTAG testing before configuration when some of the Stratix II GX pins drive or receive from other devices on the board using voltage-referenced standards. Since the Stratix II GX device may not be configured before JTAG testing, the I/O pins may not be configured for appropriate electrical standards for chip-to-chip communication. Programming these I/O standards via JTAG allows you to fully test I/O connections to other devices.

A device operating in JTAG mode uses four required pins, `TDI`, `TDO`, `TMS`, and `TCK`, and one optional pin, `TRST`. The `TCK` pin has an internal weak pull-down resistor, while the `TDI`, `TMS`, and `TRST` pins have weak internal pull-up resistors. The JTAG input pins are powered by the 3.3-V `VCCPD` pins. The `TDO` output pin is powered by the `VCCIO` power supply in I/O bank 4.

Stratix II GX devices also use the JTAG port to monitor the logic operation of the device with the SignalTap® II embedded logic analyzer. Stratix II GX devices support the JTAG instructions shown in Table 3–1.

Stratix II GX devices must be within the first eight devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Stratix II GX devices appear after the eighth device in the JTAG chain, they will fail configuration. This does not affect SignalTap II embedded logic analysis.

Table 4–3. Stratix II GX Device Recommended Operating Conditions (Part 2 of 2) Note (1)					
Symbol	**Parameter**	**Conditions**	**Minimum**	**Maximum**	**Unit**
T_J	Operating junction temperature	For commercial use	0	85	C
		For industrial use	–40	100	C

Notes to Table 4–3:
(1) Supply voltage specifications apply to voltage readings taken at the device pins, not at the power supply.
(2) During transitions, the inputs may overshoot to the voltage shown in Table 4–2 based upon the input duty cycle. The DC case is equivalent to 100% duty cycle. During transitions, the inputs may undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically from ground to V_{CC}.
(4) V_{CCPD} must ramp-up from 0 V to 3.3 V within 100 µs to 100 ms. If V_{CCPD} is not ramped up within this specified time, the Stratix II GX device will not configure successfully. If the system does not allow for a V_{CCPD} ramp-up time of 100 ms or less, hold `nCONFIG` low until all power supplies are reliable.
(5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT}, V_{CCPD}, and V_{CCIO} are powered.
(6) V_{CCIO} maximum and minimum conditions for PCI and PCI-X are shown in parentheses.

Transceiver Block Characteristics

Tables 4–4 through 4–6 contain transceiver block specifications.

Table 4–4. Stratix II GX Transceiver Block Absolute Maximum Ratings Note (1)					
Symbol	**Parameter**	**Conditions**	**Minimum**	**Maximum**	**Units**
V_{CCA}	Transceiver block supply voltage	Commercial and industrial	–0.5	4.6	V
V_{CCP}	Transceiver block supply voltage	Commercial and industrial	–0.5	1.8	V
V_{CCR}	Transceiver block supply Voltage	Commercial and industrial	–0.5	1.8	V
V_{CCT}	Transceiver block supply voltage	Commercial and industrial	–0.5	1.8	V
V_{CCT_B}	Transceiver block supply voltage	Commercial and industrial	–0.5	1.8	V
V_{CCL}	Transceiver block supply voltage	Commercial and industrial	–0.5	1.8	V
V_{CCH_B}	Transceiver block supply voltage	Commercial and industrial	–0.5	2.4	V

Note to Table 4–4:
(1) The device can tolerate prolonged operation at this absolute maximum, as long as the maximum specification is not violated.

Table 4–13. Typical Pre-Emphasis (First Post-Tap), Note (1) (Part 2 of 2)

V_{CCH} TX = 1.5 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
1400				20%	26%	33%	41%	51%	58%	67%	77%	86%

Note to Table 4–13:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–14. Typical Pre-Emphasis (First Post-Tap), Note (1)

V_{CCH} TX = 1.5 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
	TX Term = 120 Ω											
240	45%											
480		41%	76%	114%	166%	257%	355%					
720		23%	38%	55%	84%	108%	137%	179%	226%	280%	405%	477%
960		15%	24%	36%	47%	64%	80%	97%	122%	140%	170%	196%
1200			18%	22%	30%	41%	51%	63%	77%	86%	98%	116%

Note to Table 4–14:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–15. Typical Pre-Emphasis (First Post-Tap), Note (1) (Part 1 of 2)

V_{CCH} TX = 1.5 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
	TX Term = 150 Ω											
300	32%	85%										

Table 4–15. Typical Pre-Emphasis (First Post-Tap), Note (1) (Part 2 of 2)

V_{CCH} TX = 1.5 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
600		33%	53%	80%	115%	157%	195%	294%	386%			
900		19%	28%	38%	56%	70%	86%	113%	133%	168%	196%	242%
1200			17%	22%	31%	40%	52%	62%	75%	86%	96%	112%

Note to Table 4–15:
(1) Applicable to data rates from 600 Mbps to 6.375 Gbps. Specification is for measurement at the package ball.

Table 4–16. Typical Pre-Emphasis (First Post-Tap), Note (1)

V_{CCH} TX = 1.2 V	First Post Tap Pre-Emphasis Level											
V_{OD} Setting (mV)	1	2	3	4	5	6	7	8	9	10	11	12
	TX Term = 100 Ω											
320	24%	61%	114%									
480		31%	55%	86%	121%	170%	232%	333%				
640		20%	35%	54%	72%	95%	124%	157%	195%	233%	307%	373%
800			23%	36%	49%	64%	81%	97%	117%	140%	161%	195%
960			18%	25%	35%	44%	57%	69%	82%	94%	108%	127%

Note to Table 4–16:
(1) Applicable to data rates from 600 Mbps to 3.125 Gbps. Specification is for measurement at the package ball.

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 19 of 19)											
Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	

Notes to Table 4–19:

(1) Dedicated REFCLK pins were used to drive the input reference clocks.
(2) Jitter numbers specified are valid for the stated conditions only.
(3) Refer to the protocol characterization documents for detailed information.
(4) HiGig configuration is available in a -3 speed grade only. For more information, refer to the *Stratix II GX Transceiver Architecture Overview* chapter in volume 2 of the *Stratix II GX Device Handbook*.
(5) Stratix II GX transceivers meet CEI jitter generation specification of 0.3 UI for a V_{OD} range of 400 mV to 1000 mV.
(6) The Sinusoidal Jitter Tolerance Mask is defined only for low voltage (LV) variant of CPRI.
(7) The jitter numbers for SONET/SDH are compliant to the GR-253-CORE Issue 3 Specification.
(8) The jitter numbers for Fibre Channel are compliant to the FC-PI-4 Specification revision 6.10.
(9) The jitter numbers for XAUI are compliant to the IEEE802.3ae-2002 Specification.
(10) The jitter numbers for PCI Express are compliant to the PCIe Base Specification 2.0.
(11) The jitter numbers for Serial RapidIO are compliant to the RapidIO Specification 1.3.
(12) The jitter numbers for GIGE are compliant to the IEEE802.3-2002 Specification.
(13) The jitter numbers for HiGig are compliant to the IEEE802.3ae-2002 Specification.
(14) The jitter numbers for (OIF) CEI are compliant to the OIF-CEI-02.0 Specification.
(15) The jitter numbers for CPRI are compliant to the CPRI Specification V2.1.
(16) The HD-SDI and 3G-SDI jitter numbers are compliant to the SMPTE292M and SMPTE424M Specifications.
(17) The Fibre Channel transmitter jitter generation numbers are compliant to the specification at β_T interoperability point.
(18) The Fibre Channel receiver jitter tolerance numbers are compliant to the specification at β_R interoperability point.

Table 4–20 provides information on recommended input clock jitter for each mode.

Table 4–20. Recommended Input Clock Jitter (Part 1 of 2)						
Mode	Reference Clock (MHz)	Vectron LVPECL XO Type/Model	Frequency Range (MHz)	RMS Jitter (12 kHz to 20 MHz) (ps)	Period Jitter (Peak to Peak) (ps)	Phase Noise at 1 MHz (dB c/Hz)
PCI-E	100	VCC6-Q/R	10 to 270	0.3	23	-149.9957
(OIF) CEI PHY	156.25	VCC6-Q/R	10 to 270	0.3	23	-146.2169
	622.08	VCC6-Q	270 to 800	2	30	Not available
GIGE	62.5	VCC6-Q/R	10 to 270	0.3	23	-149.9957
	125	VCC6-Q/R	10 to 270	0.3	23	-146.9957
XAUI	156.25	VCC6-Q/R	10 to 270	0.3	23	-146.2169

Table 4–21. PCS Latency (Part 2 of 2) Note (1)

Functional Mode	Configuration	Transmitter PCS Latency					
		TX PIPE	TX Phase Comp FIFO	Byte Serializer	TX State Machine	8B/10B Encoder	Sum (2)
Serial RapidIO	1.25 Gbps, 2.5 Gbps, 3.125 Gbps	-	2-3	1	-	0.5	4-5
SDI	HD 10-bit channel width	-	2-3	1	-	1	4-5
	HD, 3G 20-bit channel width	-	2-3	1	-	0.5	4-5
BASIC Single Width	8-bit/10-bit channel width	-	2-3	1	-	1	4-5
	16-bit/20-bit channel width	-	2-3	1	-	0.5	4-5
BASIC Double Width	16-bit/20-bit channel width	-	2-3	1	-	1	4-5
	32-bit/40-bit channel width	-	2-3	1	-	0.5	4-5
	Parallel Loopback/ BIST	-	2-3	1	-	1	4-5

Notes to Table 4–21:

(1) The latency numbers are with respect to the PLD-transceiver interface clock cycles.

(2) The total latency number is rounded off in the Sum column.

(3) For CPRI 614 Mbps and 1.228 Gbps data rates, the Quartus II software customizes the PLD-transceiver interface clocking to achieve zero clock cycle uncertainty in the transmitter phase compensation FIFO latency. For more details, refer to the *CPRI Mode* section in the *Stratix II GX Transceiver Architecture Overview* chapter in volume 2 of the *Stratix II GX Device Handbook*.

Table 4–22. PCS Latency (Part 3 of 3) Note (1)

Functional Mode	Configuration	Receiver PCS Latency									
		Word Aligner	Deskew FIFO	Rate Matcher (3)	8B/10B Decoder	Receiver State Machine	Byte De-serializer	Byte Order	Receiver Phase Comp FIFO	Receiver PIPE	Sum (2)
BASIC Double Width	16/20-bit channel width; with Rate Matcher	4-5	-	11-13	1	-	1	1	1-2	-	19-23
	16/20-bit channel width; without Rate Matcher	4-5	-	-	1	-	1	1	1-2	-	8-10
	32/40-bit channel width; with Rate Matcher	2-2.5	-	5.5-6.5	0.5	-	1	1	1-2	-	11-14
	32/40-bit channel width; without Rate Matcher	2-2.5	-	-	0.5	-	1	1-3	1-2	-	6-9

Notes to Table 4–21:

(1) The latency numbers are with respect to the PLD-transceiver interface clock cycles.

(2) The total latency number is rounded off in the Sum column.

(3) The rate matcher latency shown is the steady state latency. Actual latency may vary depending on the skip ordered set gap allowed by the protocol, actual PPM difference between the reference clocks, and so forth.

(4) For CPRI 614 Mbps and 1.228 Gbps data rates, the Quartus II software customizes the PLD-transceiver interface clocking to achieve zero clock cycle uncertainty in the receiver phase compensation FIFO latency. For more details, refer to the *CPRI Mode* section in the *Stratix II GX Transceiver Architecture Overview* chapter in volume 2 of the *Stratix II GX Device Handbook*

Table 4–87. Stratix II GX I/O Output Delay for Row Pins (Part 2 of 4)								
I/O Standard	Drive Strength	Parameter	Fast Corner Industrial/ Commercial	-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit
LVCMOS	4 mA	t_{OP}	1200	2113	2217	2357	2549	ps
		t_{DIP}	1157	2058	2160	2297	2476	ps
	8 mA (1)	t_{OP}	1094	1853	1944	2067	2243	ps
		t_{DIP}	1051	1798	1887	2007	2170	ps
	12 mA (1)	t_{OP}	1061	1723	1808	1922	2089	ps
		t_{DIP}	1018	1668	1751	1862	2016	ps
2.5 V	4 mA	t_{OP}	1183	2091	2194	2332	2523	ps
		t_{DIP}	1140	2036	2137	2272	2450	ps
	8 mA	t_{OP}	1080	1872	1964	2088	2265	ps
		t_{DIP}	1037	1817	1907	2028	2192	ps
	12 mA (1)	t_{OP}	1061	1775	1862	1980	2151	ps
		t_{DIP}	1018	1720	1805	1920	2078	ps
1.8 V	2 mA	t_{OP}	1253	2954	3100	3296	3542	ps
		t_{DIP}	1210	2899	3043	3236	3469	ps
	4 mA	t_{OP}	1242	2294	2407	2559	2763	ps
		t_{DIP}	1199	2239	2350	2499	2690	ps
	6 mA	t_{OP}	1131	2039	2140	2274	2462	ps
		t_{DIP}	1088	1984	2083	2214	2389	ps
	8 mA (1)	t_{OP}	1100	1942	2038	2166	2348	ps
		t_{DIP}	1057	1887	1981	2106	2275	ps
1.5 V	2 mA	t_{OP}	1213	2530	2655	2823	3041	ps
		t_{DIP}	1170	2475	2598	2763	2968	ps
	4 mA (1)	t_{OP}	1106	2020	2120	2253	2440	ps
		t_{DIP}	1063	1965	2063	2193	2367	ps
SSTL-2 Class I	8 mA	t_{OP}	1050	1759	1846	1962	2104	ps
		t_{DIP}	1007	1704	1789	1902	2031	ps
	12 mA (1)	t_{OP}	1026	1694	1777	1889	2028	ps
		t_{DIP}	983	1639	1720	1829	1955	ps
SSTL-2 Class II	16 mA (1)	t_{OP}	992	1581	1659	1763	1897	ps
		t_{DIP}	949	1526	1602	1703	1824	ps

Table 4–91. Stratix II GX Maximum Output Clock Rate for Column Pins (Part 2 of 3)					
I/O Standard	**Drive Strength**	**-3 Speed Grade**	**-4 Speed Grade**	**-5 Speed Grade**	**Unit**
SSTL-18 Class I	4 mA	200	150	150	MHz
	6 mA	350	250	200	MHz
	8 mA	450	300	300	MHz
	10 mA	500	400	400	MHz
	12 mA *(1)*	700	550	400	MHz
SSTL-18 Class II	8 mA	200	200	150	MHz
	16 mA	400	350	350	MHz
	18 mA	450	400	400	MHz
	20 mA *(1)*	550	500	450	MHz
1.8-V HSTL Class I	4 mA	300	300	300	MHz
	6 mA	500	450	450	MHz
	8 mA	650	600	600	MHz
	10 mA	700	650	600	MHz
	12 mA *(1)*	700	700	650	MHz
1.8-V HSTL Class II	16 mA	500	500	450	MHz
	18 mA	550	500	500	MHz
	20 mA *(1)*	650	550	550	MHz
1.5-V HSTL Class I	4 mA	350	300	300	MHz
	6 mA	500	500	450	MHz
	8 mA	700	650	600	MHz
	10 mA	700	700	650	MHz
	12 mA *(1)*	700	700	700	MHz
1.5-V HSTL Class II	16 mA	600	600	550	MHz
	18 mA	650	600	600	MHz
	20 mA *(1)*	700	650	600	MHz
PCI	-	1000	790	670	MHz
PCI-X	-	1000	790	670	MHz
Differential SSTL-2 Class I	8 mA	400	300	300	MHz
	12 mA	400	400	350	MHz
Differential SSTL-2 Class II	16 mA	350	350	300	MHz
	20 mA	400	350	350	MHz
	24 mA	400	400	350	MHz

Table 4–105. Maximum DCD for DDIO Output on Column I/O Pins With PLL in the Clock Path (Part 2 of 2)			
Maximum DCD (ps) for Column DDIO Output I/O Standard	Stratix II GX Devices (PLL Output Feeding DDIO)		Unit
	-3 Device	-4 and -5 Device	
1.2-V HSTL	155	155	ps
LVPECL	180	180	ps

High-Speed I/O Specifications

Table 4–106 provides high-speed timing specifications definitions.

Table 4–106. High-Speed Timing Specifications and Definitions	
High-Speed Timing Specifications	Definitions
t_C	High-speed receiver/transmitter input and output clock period.
f_{HSCLK}	High-speed receiver/transmitter input and output clock frequency.
J	Deserialization factor (width of parallel data bus).
W	PLL multiplication factor.
t_{RISE}	Low-to-high transmission time.
t_{FALL}	High-to-low transmission time.
Timing unit interval (TUI)	The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency × Multiplication Factor) = t_C/w).
f_{IN}	Fast PLL input clock frequency
f_{HSDR}	Maximum/minimum LVDS data transfer rate (f_{HSDR} = 1/TUI), non-DPA.
$f_{HSDRDPA}$	Maximum/minimum LVDS data transfer rate ($f_{HSDRDPA}$ = 1/TUI), DPA.
Channel-to-channel skew (TCCS)	The timing difference between the fastest and the slowest output edges including t_{CO} variation and clock skew across channels driven by the same fast PLL. The clock is included in the TCCS measurement.
Sampling window (SW)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window.
Input jitter	Peak-to-peak input jitter on high-speed PLLs.
Output jitter	Peak-to-peak output jitter on high-speed PLLs.
t_{DUTY}	Duty cycle on high-speed transmitter output clock.
t_{LOCK}	Lock time for high-speed transmitter and receiver PLLs.